



SiC MOSFET Module

SKM350MB120SCH17

Features*

- Full Silicon Carbide (SiC) power module
- High reliability 2nd Generation SiC MOSFETs
- Optimized for fast switching and lowest power losses
- High humidity robustness (HV-H3TRB proof)
- External SiC Schottky Barrier Diode embedded
- Insulated copper baseplate using DBC technology (Direct Bonded Copper)
- Improved thermal performances with Aluminium Nitride (AlN) substrate
- UL recognized, file no. E63532

Typical Applications

- High frequency power supplies
- AC inverters
- Traction APU
- EV Chargers
- Industrial Test Systems

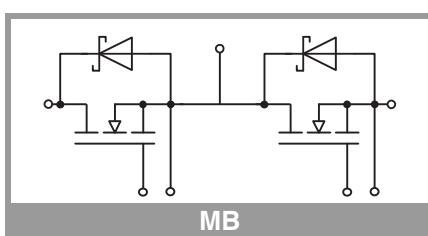
Remarks

- Case temperature limited to $T_C = 125^\circ\text{C}$ max.
- Recommended $T_{jop} = -40 \dots +150^\circ\text{C}$
- Gate-Source SURGE VOLTAGE ($t_{surge} < 300\text{ns}$), $V_{GS_surge} = -10\text{V} \dots +26\text{V}$

Absolute Maximum Ratings		Values	Unit
Symbol	Conditions		
MOSFET			
V_{DSS}		1200	V
I_D	$T_j = 175^\circ\text{C}$	$T_c = 25^\circ\text{C}$	478
		$T_c = 80^\circ\text{C}$	380
I_{DM}		1280	A
I_{DRM}		904	A
V_{GS}		-6 ... 22	V
T_j		-40 ... 175	$^\circ\text{C}$
Integrated body diode			
I_{FM}		1280	A
I_{FRM}		904	A

Absolute Maximum Ratings		Values	Unit
Symbol	Conditions		
Inverse diode			
V_{RRM}	$T_j = 25^\circ\text{C}$	1200	V
I_F	$T_j = 175^\circ\text{C}$	$T_c = 25^\circ\text{C}$	187
		$T_c = 80^\circ\text{C}$	143
I_{Fnom}		100	A
I_{FRM}		300	A
I_{FSM}	$t_p = 8.3\text{ ms, sin }180^\circ, T_j = 25^\circ\text{C}$	373	A
T_j		-40 ... 175	$^\circ\text{C}$

Absolute Maximum Ratings		Values	Unit
Symbol	Conditions		
Module			
$I_{t(RMS)}$		500	A
T_{stg}	module without TIM	-40 ... 125	$^\circ\text{C}$
V_{isol}	AC sinus 50 Hz, $t = 1\text{ min}$	4000	V





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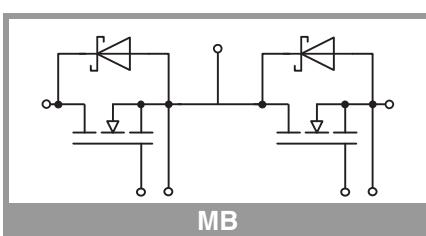
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($t_{\text{surge}} < 300\text{ns}$), $V_{GS, \text{surge}} = -10\text{V} \dots +26\text{V}$

Characteristics		Symbol	Conditions	min.	typ.	max.	Unit
MOSFET							
$V_{(BR)DSS}$	$V_{GS} = 0 \text{ V}$, $I_D = 1 \text{ mA}$, $T_j = 25 \text{ }^\circ\text{C}$			1200			V
$V_{GS(\text{th})}$	$V_{DS} = V_{GS}$, $I_D = 71.2 \text{ mA}$			1.6		4	V
I_{DSS}	$V_{GS} = 0 \text{ V}$, $V_{DS} = 1200 \text{ V}$, $T_j = 25 \text{ }^\circ\text{C}$					2	mA
I_{GSS}	$V_{GS} = 22 \text{ V}$, $V_{DS} = 0 \text{ V}$					800	nA
$R_{DS(\text{on})}$	$V_{GS} = 18 \text{ V}$		$T_j = 25 \text{ }^\circ\text{C}$		5.6	7.0	$\text{m}\Omega$
	$I_D = 176 \text{ A}$ chiplevel		$T_j = 150 \text{ }^\circ\text{C}$		9.5		$\text{m}\Omega$
C_{iss}	$V_{GS} = 0 \text{ V}$		$T_j = 25 \text{ }^\circ\text{C}$		34.5		nF
C_{oss}	$V_{DS} = 800 \text{ V}$		$T_j = 25 \text{ }^\circ\text{C}$		1.10		nF
C_{rss}	$f = 1 \text{ MHz}$		$T_j = 25 \text{ }^\circ\text{C}$		0.15		nF
R_{Gint}	$T_j = 25 \text{ }^\circ\text{C}$				0.6		Ω
Q_G	$V_{DD}=600\text{V}$, $V_{GS}=-5 \dots 20\text{V}$, $I_D = 350 \text{ A}$				1850		nC
$t_{d(\text{on})}$	$V_{DD} = 600 \text{ V}$		$T_j = 150 \text{ }^\circ\text{C}$		64		ns
t_r	$I_D = 175 \text{ A}$		$T_j = 150 \text{ }^\circ\text{C}$		10		ns
$t_{d(\text{off})}$	$V_{GS} = -5 \dots 20 \text{ V}$		$T_j = 150 \text{ }^\circ\text{C}$		183		ns
t_f	$R_{Gon} = 0.5 \Omega$		$T_j = 150 \text{ }^\circ\text{C}$		33		ns
E_{on}	$R_{Goff} = 0.5 \Omega$ $di/dt_{on} = 13.5 \text{ kA}/\mu\text{s}$		$T_j = 150 \text{ }^\circ\text{C}$		1.69		mJ
E_{off}	$di/dt_{off} = 7.1 \text{ kA}/\mu\text{s}$						
	$dv/dt_{on} = 10.5 \text{ kV}/\mu\text{s}$		$T_j = 150 \text{ }^\circ\text{C}$		1.31		mJ
	$dv/dt_{off} = 28 \text{ kV}/\mu\text{s}$						
$R_{th(j-c)}$	per MOSFET				0.055		K/W
$R_{th(c-s)}$	per MOSFET ($\lambda_{\text{grease}}=0.81 \text{ W}/(\text{m}^*\text{K})$)				0.03		K/W

Characteristics		Symbol	Conditions	min.	typ.	max.	Unit
Inverse diode							
$V_F = V_{EC}$	$I_F = 100 \text{ A}$		$T_j = 25 \text{ }^\circ\text{C}$		1.40	1.60	V
	chiplevel		$T_j = 150 \text{ }^\circ\text{C}$		1.80	2.10	V
V_{FO}	chiplevel		$T_j = 25 \text{ }^\circ\text{C}$		0.95	1.05	V
			$T_j = 150 \text{ }^\circ\text{C}$		0.80	0.90	V
r_F	chiplevel		$T_j = 25 \text{ }^\circ\text{C}$		4.5	5.5	$\text{m}\Omega$
			$T_j = 150 \text{ }^\circ\text{C}$		10.0	12	$\text{m}\Omega$
C_j	parallel to C_{oss} , $f = 1 \text{ MHz}$, $V_R = 800 \text{ V}$, $T_j = 25 \text{ }^\circ\text{C}$				0.42		nF
Q_c	$V_R = 800 \text{ V}$, $\text{d}i/\text{d}t_{\text{off}} = 500 \text{ A}/\mu\text{s}$, $T_j = 25 \text{ }^\circ\text{C}$				0.33		μC
$R_{th(j-c)}$	per diode					0.24	K/W
$R_{th(c-s)}$	per diode ($\lambda_{\text{grease}} = 0.81 \text{ W}/(\text{m}^*\text{K})$)				0.076		K/W





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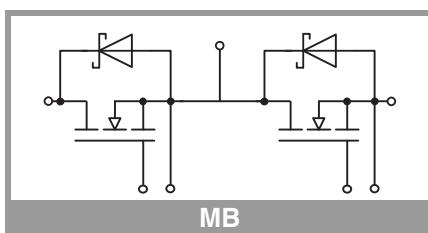
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Characteristics		min.	typ.	max.	Unit
Symbol	Conditions				
Module					
L_{DS}			15		nH
$R_{DD+SS'}$	measured per switch	$T_C = 25^\circ\text{C}$	0.55		$\text{m}\Omega$
		$T_C = 125^\circ\text{C}$	0.85		$\text{m}\Omega$
$R_{th(c-s)1}$	calculated without thermal coupling ($\lambda_{grease}=0.81\text{ W}/(\text{m}^\circ\text{K})$)		0.011		K/W
$R_{th(c-s)2}$	including thermal coupling, T_s underneath module ($\lambda_{grease}=0.81\text{ W}/(\text{m}^\circ\text{K})$)		0.015		K/W
M_s	to heat sink M6	3	5		Nm
M_t	to terminals M6	2.5	5		Nm
					Nm
w			325		g



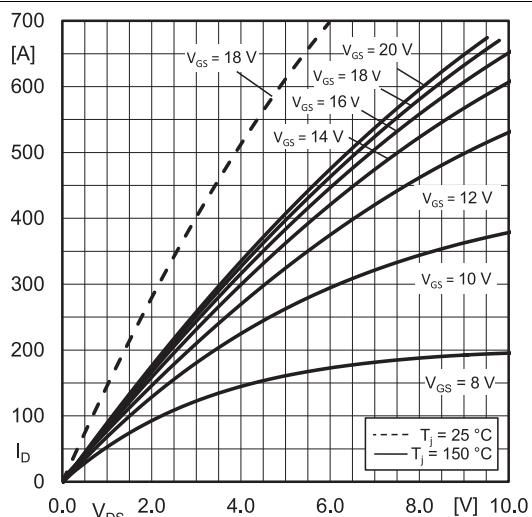


Fig.1: Typ. MOSFET forward output characteristic, incl. $R_{DD'} + SS'$

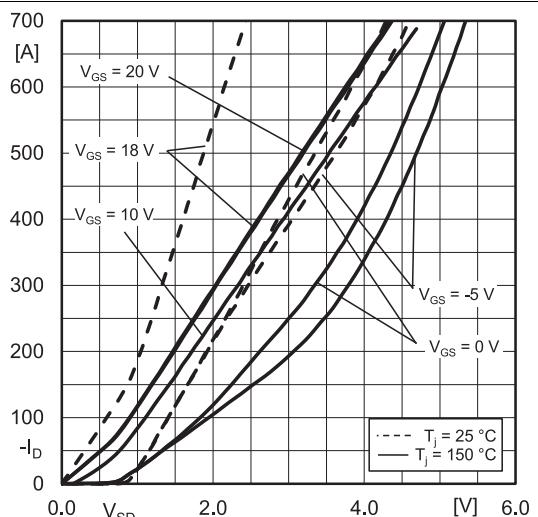


Fig. 2: Typ. reverse output characteristic, incl. $R_{DD'} + SS'$

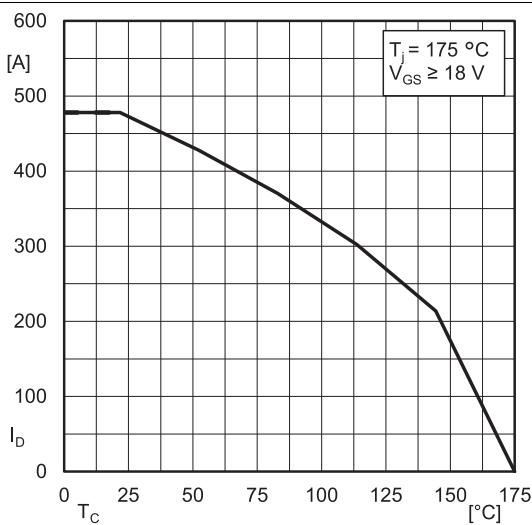


Fig. 3: Rated current vs. temperature $I_D = f (T_C)$

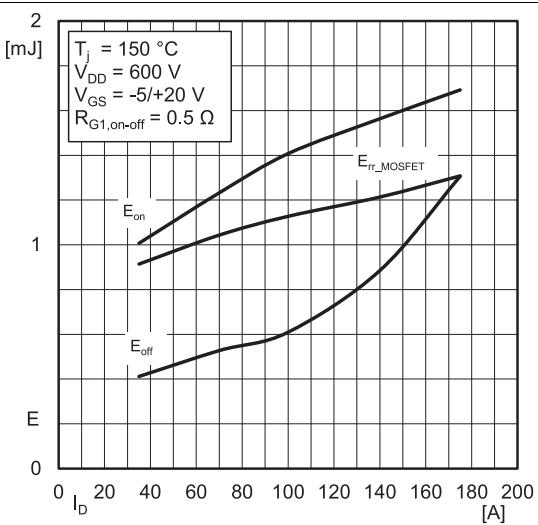


Fig. 4: Typ. switching energy $E = f (I_D)$ at R_{G1}

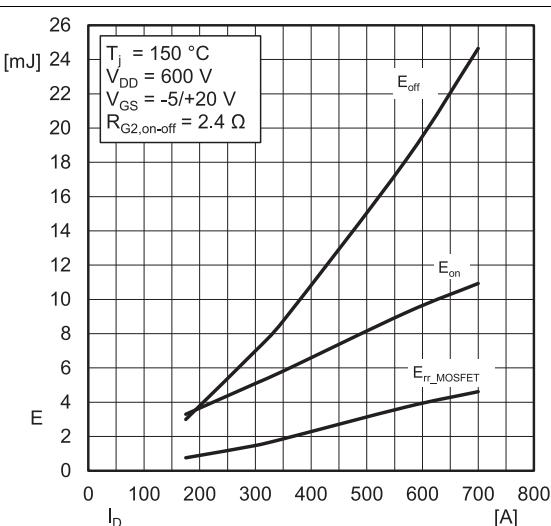


Fig. 5: Typ. switching energy $E = f (I_D)$ at R_{G2}

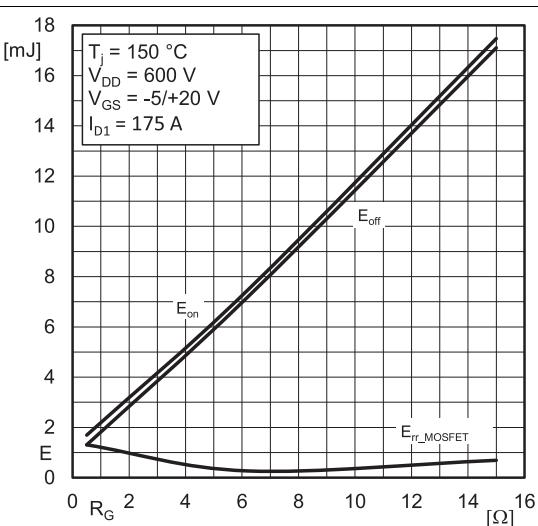


Fig. 6: Typ. switching energy $E = f (R_G)$ at I_{D1}

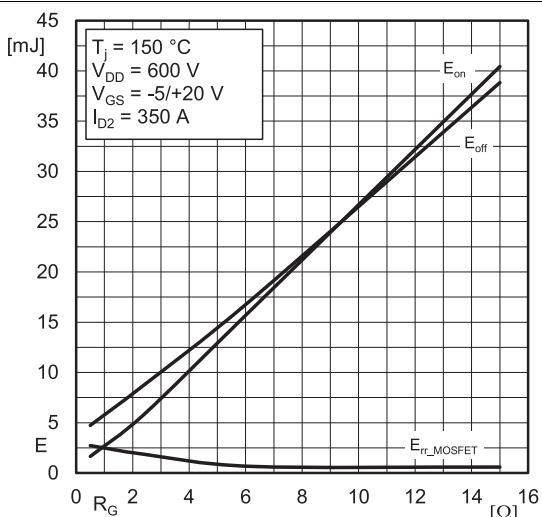


Fig. 7: Typ. switching energy $E = f (R_G)$ at I_{D2}

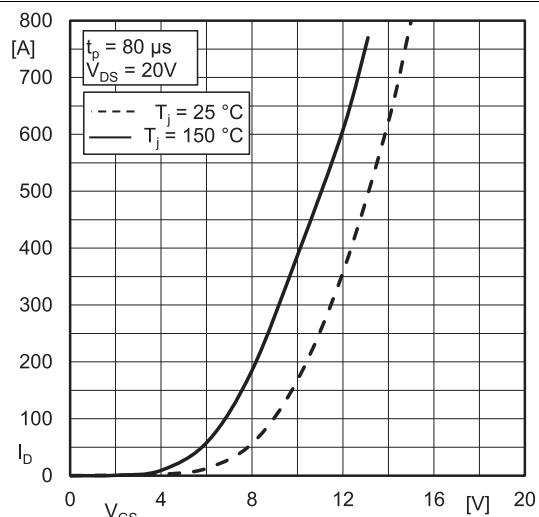


Fig. 8: Typ. MOSFET transfer characteristic

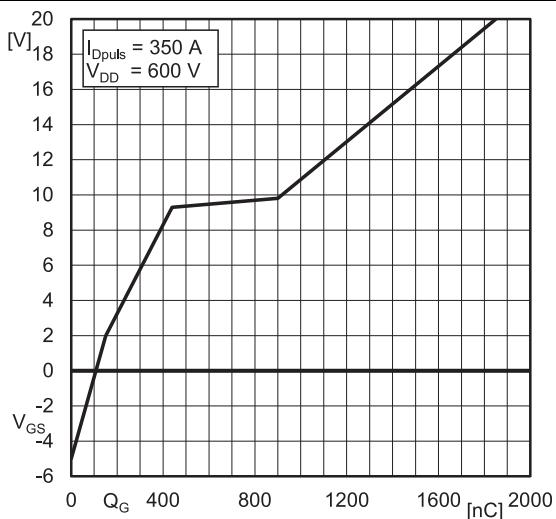


Fig. 9: Typ. gate charge characteristic

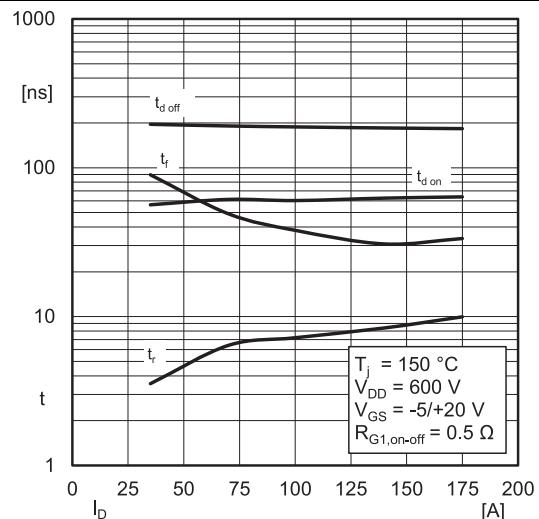


Fig. 10: Typ. switching times $t = f (I_D)$ at R_{G1}

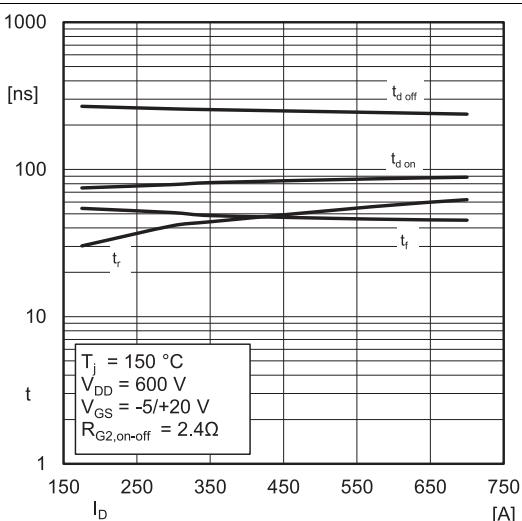


Fig. 11: Typ. switching times $t = f (I_D)$ at R_{G2}

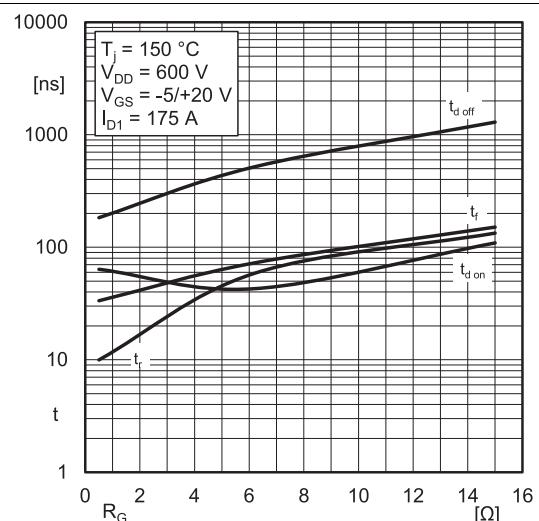


Fig. 12: Typ. switching times $t = f (R_G)$ at I_{D1}

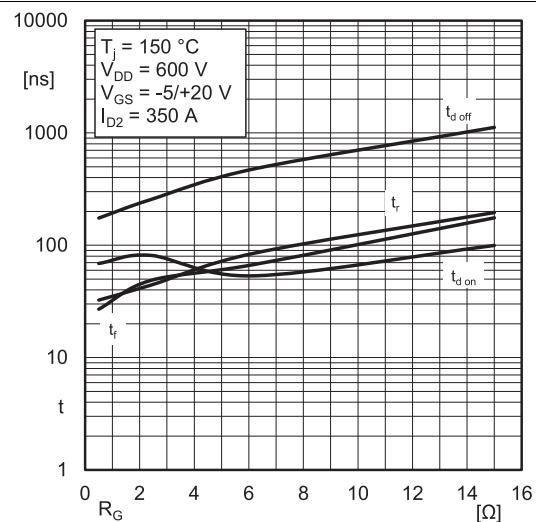


Fig. 13: Typ. switching times $t = f(R_G)$ at I_{D2}

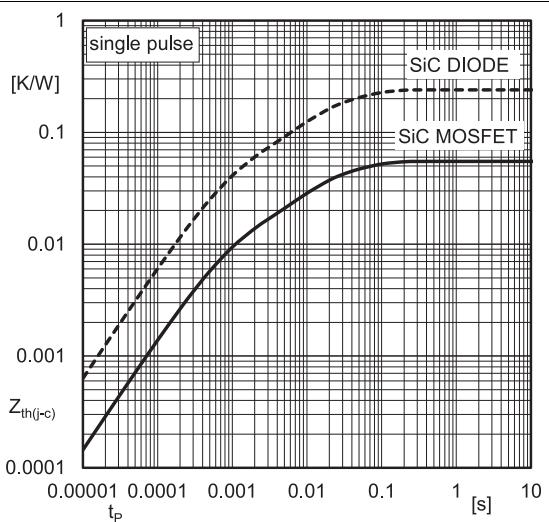


Fig. 14: Transient thermal impedance

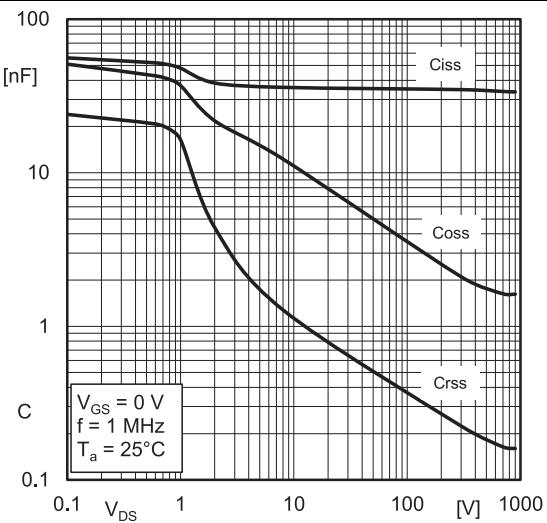
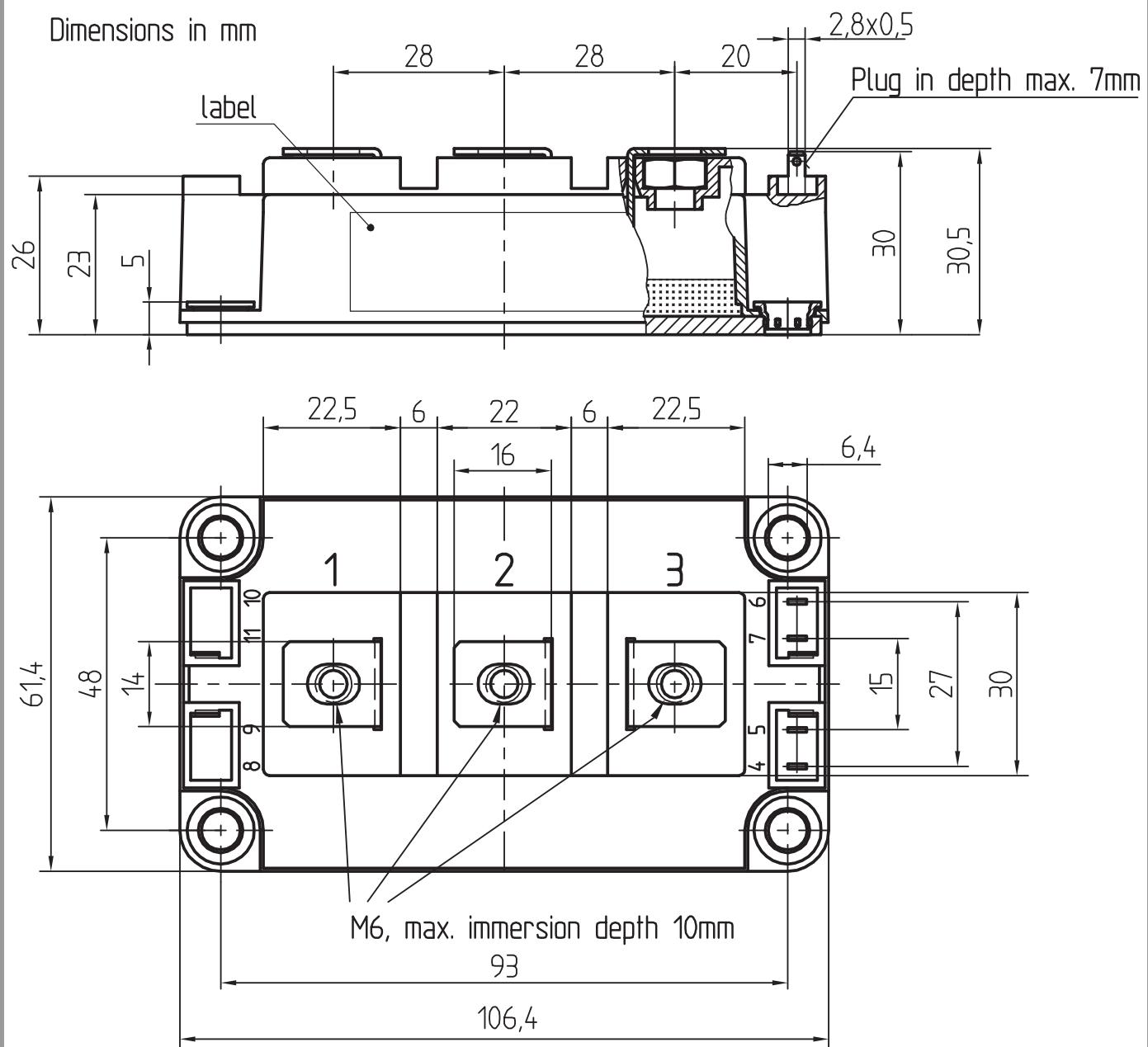
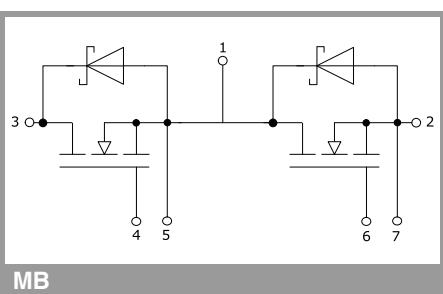


Fig. 19: Capacitances vs. drain-source voltage

Dimensions in mm

General tolerance $+\text{-} 0.5$ mm

SEMITRANS 3



MB

This is an electrostatic discharge sensitive device (ESDS) due to international standard IEC 61340.

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